

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Kenji OBARA, et al.	Examiner:
Application No.:	Art Unit:
Filed:	INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §1.97 and §1.98
For: METHOD AND APPARATUS FOR ANALYZING COMPOSITION OF DEFECTS	

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The references cited on attached form PTO/SB/08A and PTO/SB/08B are being called to the attention of the Examiner. Copies of the references are enclosed. It is respectfully requested that the cited references be expressly considered during the prosecution of this application, and the references be made of record therein and appear among the "references cited" on any patent to issue therefrom.

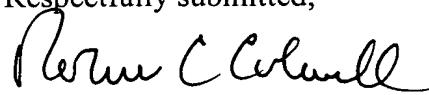
As provided for by 37 CFR 1.97(g) and (h), no inference should be made that the information and references cited are prior art merely because they are in this statement and no representation is being made that a search has been conducted or that this statement encompasses all the possible relevant information.

Applicant believes that no fee is required for submission of this statement. However, if a fee is required, the Commissioner is authorized to deduct such fee from the undersigned's Deposit Account No. 20-1430. Please deduct any additional fees from, or credit any overpayment to, the above-noted Deposit Account.

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PATENT

Respectfully submitted,



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60100084 v1

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known		
				Application Number		
				Filing Date		
				First Named Inventor		OBARA, Kenji
				Art Unit		
				Examiner Name		
Sheet	1	of		Attorney Docket Number	16869P-099000US	

U.S. PATENT DOCUMENTS+					
		Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
Examiner Initials*	Cite No. ¹	Number Kind Code ² (if known)			
	AA	US-			
	AB	US-			
	AC	US-			
	AD	US-			
	AE	US-			
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	AG	US-			
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	AQ	US-			
	AR	US-			
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FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³	Number ⁴		
	AU	JP	2000-030652	01-28-2000	Hitachi, Ltd.
	AV	JP	08-148111	06-07-1996	Hitachi, Ltd.
	AW	JP	01-143127	06-05-1989	Hitachi, Ltd.
	AX	JP	08-021803	01-23-1996	Olympus Optical
	AY	JP	10-027833	01-27-1998	JEOL LTD.
	AZ				<input type="checkbox"/>
	BA				<input type="checkbox"/>
	BB				<input type="checkbox"/>

Examiner Signature	Date Considered
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¹EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ² Applicant's unique citation designation number (optional). ³ Kind Codes of U.S. Patent Documents at www.uspto.gov or MPEP 901.04. ⁴ Enter Office that issued the document, by the two-letter code (WIPO Standard ST-3). ⁵ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁶ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST-16 if possible. ⁷ Applicant is to place a check mark here if English language Translation is attached.
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